Unit: mm

TOSHIBA TRANSISTOR SILICON NPN TRIPLE DIFFUSED MESA TYPE

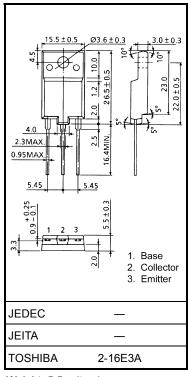
# 2SD2498

HORIZONTAL DEFLECTION OUTPUT FOR HIGH RESOLUTION DISPLAY, COLOR TV HIGH SPEED SWITCHING APPLICATIONS

- High Voltage :  $V_{CBO} = 1500 V$
- Low Saturation Voltage  $: V_{CE} (sat) = 5 V (Max.)$
- High Speed :  $t_f = 0.4 \ \mu s \ (Typ.)$
- Collector Metal (Fin) is Fully Covered with Mold Resin

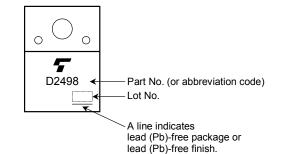
### MAXIMUM RATINGS (Tc = 25°C)

CHARACTERISTIC		SYMBOL	RATING	UNIT	
Collector-Base Voltage		V <sub>CBO</sub>	1500	V	
Collector-Emitter Voltage		V <sub>CEO</sub>	600	V	
Emitter-Base Voltage		V <sub>EBO</sub>	5	V	
Collector Current	DC	Ι <sub>C</sub>	6	A	
	Pulse	I <sub>CP</sub>	12		
Base Current		Ι <sub>Β</sub>	3	А	
Collector Power Dissipation		P <sub>C</sub>	50	W	
Junction Temperature		Tj	150	°C	
Storage Temperature Range		T <sub>stg</sub>	-55~150	°C	



Weight: 5.5 g (typ.)

### MARKING

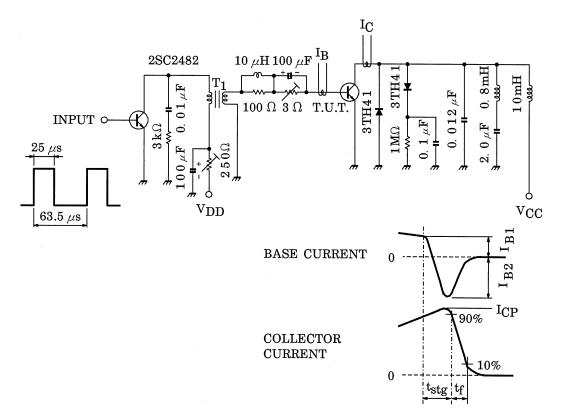


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# ELECTRICAL CHARACTERISTICS (Tc = 25°C)

CHARACTERISTIC		SYMBOL	TEST CONDITION	MIN	TYP.	MAX	UNIT
Collector Cut-off Current		I <sub>CBO</sub>	V <sub>CB</sub> = 1500 V, I <sub>E</sub> = 0	-	—	1	mA
Emitter Cut-off Current		I <sub>EBO</sub>	V <sub>EB</sub> = 5 V, I <sub>C</sub> = 0	_	_	10	μA
Collector-Emitter Breakdown Voltage		V (BR) CEO	I <sub>C</sub> = 10 mA, I <sub>B</sub> = 0	600	_	_	V
DC Current Gain		h <sub>FE (1)</sub>	V <sub>CE</sub> = 5 V, I <sub>C</sub> = 1 A	10	_	30	
		h <sub>FE (2)</sub>	V <sub>CE</sub> = 5 V, I <sub>C</sub> = 4A	5	_	9	
Collector-Emitter Saturation Voltage		V <sub>CE (sat)</sub>	I <sub>C</sub> = 4A, I <sub>B</sub> = 0.8 A	_	_	5	V
Base-Emitter Saturation Voltage		V <sub>BE (sat)</sub>	I <sub>C</sub> = 4 A, I <sub>B</sub> = 0.8 A	_	0.9	1.2	V
Transition Frequency		f <sub>T</sub>	V <sub>CE</sub> = 10 V, I <sub>C</sub> = 0.1 A	_	2	_	MHz
Collector Output Capacitance		C <sub>ob</sub>	V <sub>CB</sub> = 10 V, I <sub>E</sub> = 0, f = 1 MHz	—	95	_	pF
Switching Time (Fig.1)	Storage Time	t <sub>stg</sub>	I <sub>CP</sub> = 4 A, I <sub>B1</sub> (end) = 0.8 A f <sub>H</sub> = 15.75 kHz	—	7	10	μs
	Fall Time	t <sub>f</sub>		_	0.4	0.7	

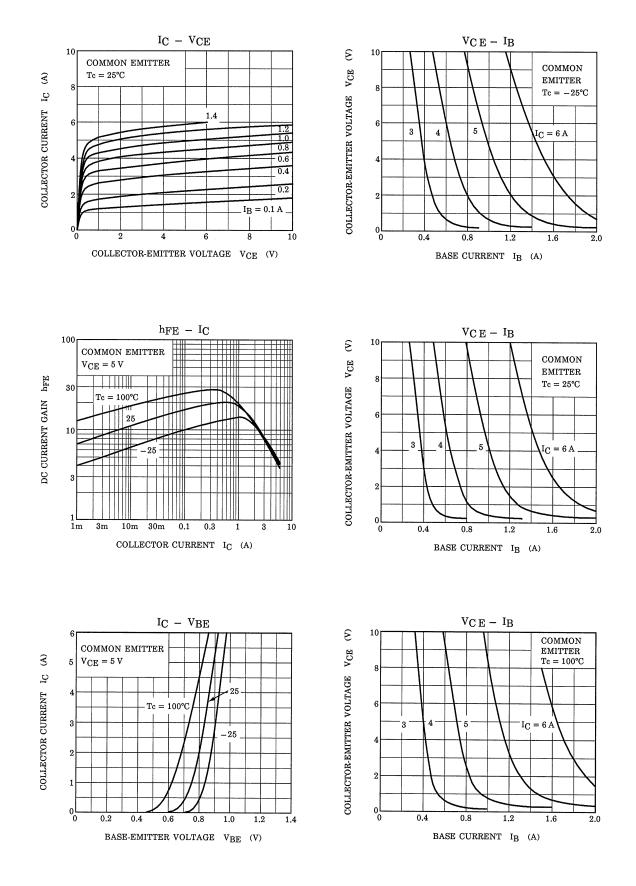
## Fig.1 SWITCHING TIME TEST CIRCUIT



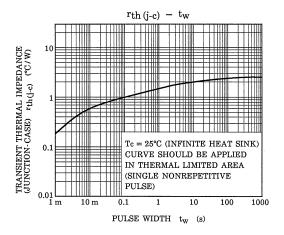
Base Current Gradient

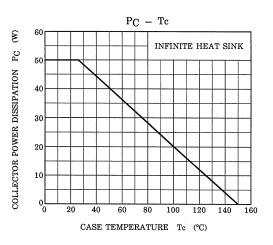
$$dI_B/dt = \frac{I_{B1} + I_{B2}}{t_{stg}} \left(A/\mu s\right)$$

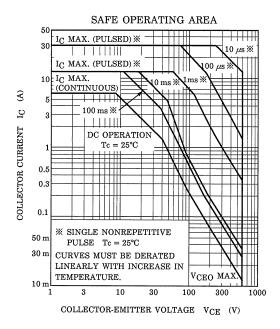
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